

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE  
BEFORE THE PATENT TRIAL AND APPEAL BOARD

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APPLIED MATERIALS, INC.,

Petitioner

v.

OCEAN SEMICONDUCTOR LLC,

Patent Owner.

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Case IPR: Unassigned  
U.S. Patent No. 6,836,691

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**PETITION FOR *INTER PARTES* REVIEW  
OF U.S. PATENT NO. 6,836,691**

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**EXHIBIT LIST**

<b>Exhibit No.</b>	<b>Description</b>
1001	U.S. Patent No. 6,836,691 (“’691 patent”)
1002	Declaration of Miltiadis Hatalis, Ph.D.
1003	<i>Curriculum Vitae</i> of Miltiadis Hatalis, Ph.D.
1004	File Wrapper for the ’691 patent
1005	Funk et al., U.S. Patent No. 7,123,980 (filed Mar. 23, 2005; issued Oct. 17, 2006) (“Funk”)
1006	Funk, U.S. Provisional Application No. 60/414,425 (filed Sept. 30, 2002; expired July 19, 2004)
1007	Funk et al., International Publication No. WO 2004/031875 (filed Sept. 25, 2003; published Apr. 15, 2004)
1008	Stoddard et al., U.S. Patent No. 6,587,744 (filed June 20, 2000; issued July 1, 2003)
1009	File Wrapper for Funk
1010	Roger E. Bohn and Christian Terwiesch, <i>The Economics of Yield-Driven Processes</i> , J. Operations Management, 18: 41-59 (1999)
1011	Robert C. Leachman and David A. Hodges, <i>Benchmarking Semiconductor Manufacturing</i> , IEEE Transactions on Semiconductor Manufacturing, 9: 158-69 (1996)
1012	Gardner, et al., <i>Equipment Fault Detection Using Spatial Signatures</i> , IEEE Transactions on Components, Packaging, and Manufacturing Technology—Part C, 20: 295-304 (1997)
1013	John McGehee, <i>The MMST Computer-Integrated Manufacturing System Framework</i> , IEEE Transactions on Semiconductor Manufacturing, 7: 107-16 (1994)
1014	Jula, P. et al., <i>Comparing the Economic Impact of Alternative Metrology Methods in Semiconductor Manufacturing</i> , IEEE Transactions on Semiconductor Manufacturing, Vol. 15, No. 4 (November 2002)

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Exhibit No.	Description
1015	Richard J. Markle and Elfido Coss, Jr., <i>Data requirements and communication issues for advanced process control</i> , J. of Vacuum Sci. & Tech. A 19, 1241 (2001).
1016	Musacchio, J., et al., <i>On the Utility of Run to Run Control in Semiconductor Manufacturing</i> , IEEE International Symposium on Semiconductor Manufacturing Conference Proceedings, D-9–D-12 (1997)
1017	Jerry A. Stefani and Mike Anderson, <i>Practical Issues in the Deployment of a Run-to-Run Control System in a Semiconductor Manufacturing Facility</i> , Proc. SPIE 3742, Process and Equipment Control in Microelectronic Manufacturing, 52-64 (April 23, 1999)
1018	Gabriel G. Barna, <i>APC in the Semiconductor Industry, History and Near Term Prognosis</i> , IEEE/SEMI 1996 Advanced Semiconductor Manufacturing Conference and Workshop. Theme-Innovative Approaches to Growth in the Semiconductor Industry. ASMC 96 Proceedings, 364-69 (1996)
1019	Limanond, S., et al., <i>Monitoring and Control of Semiconductor Manufacturing Processes</i> , IEEE Control Systems Magazine, 18:46-58 (1998)
1020	Ison, A.M., et al., <i>Fault Diagnosis of Plasma Etch Equipment</i> , IEEE International Symposium on Semiconductor Manufacturing Conference Proceedings (1997)
1021	Mark Melliar-Smith and Alain C. Diebold, <i>Metrology Needs for the Semiconductor Industry Over the Next Decade</i> , AIP Conference Proceedings 449, 3 (1998).
1022	Chris J. McDonald, <i>New tools for yield improvement in integrated circuit manufacturing: can they be applied to reliability?</i> , Microelectronics Reliability 39 (June 1999)
1023	Handbook of Thin Film Deposition Process and Technologies (2nd Ed. 2002); Chapter 6 Keefer, M. et al., “The Role of Metrology and Inspection in Semiconductor Processing”

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